

Notice of References Cited	Application/Control No. 10/580,510		Applicant(s)/Patent Under Reexamination LIETZ ET AL.	
	Examiner RYAN M. STIGLIC		Art Unit 2111	Page 1 of 1

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	U	Texas Instruments; "TSB12C01A Data Manual"; Texas Instruments; Document No. SLLS219B; November 1998; pages 1-59.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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